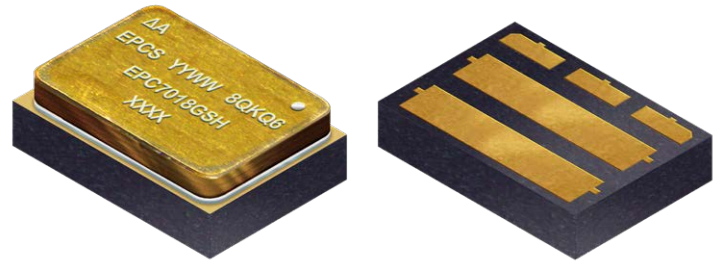


## Features

- Ultra-low  $Q_G$  For High Efficiency
- Logic Level
- Light Weight – 0.170 grams
- New Compact Hermetic Package with Dual Gate
- Source Sense Pin
- Total Dose
  - Rated to 1000 krad
- Single Event
  - SEE immunity for LET of 85 MeV/mg/cm<sup>2</sup> with  $V_{DS}$  up to 100% of rated Breakdown
- Low Dose Rate at 100 mRad/sec
  - Maintains Pre-Rad specification
- Neutron
  - Maintains Pre-Rad specification for up to  $3 \times 10^{15}$  Neutrons/cm<sup>2</sup>



## EPC7018G

**Rad Hard eGaN<sup>®</sup> 100 V, 80 A,  
6.0 mΩ Surface Mount**

### Description

EPC Space FSMD-G series of eGaN<sup>®</sup> power switching HEMTs have been specifically designed for critical applications in the high reliability or commercial satellite space environments. These devices have exceptionally high electron mobility and a low temperature coefficient resulting in very low  $R_{DS(on)}$  values. The lateral structure of the die provides for very low gate charge ( $Q_G$ ) and extremely fast switching times. These features enable faster power supply switching frequencies resulting in higher power densities, higher efficiencies and more compact packaging.

## Applications

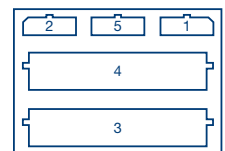
- Satellite and Avionics
- Deep Space Probes
- High Speed Rad Hard DC-DC Conversion
- Rad Hard Motor Controllers
- Nuclear Facilities

## Thermal Characteristics

Symbol	Parameter-Conditions	Value	Units
$R_{\theta JA}$	Thermal Resistance Junction to Ambient (Note 3)	48	°C/W
$R_{\theta JC}$	Thermal Resistance Junction to Case	1.53	

## I/O Pin Assignment (Bottom View)

Pin	Symbol	Description
1	G	Gate
2	G	Gate
3	D	Drain
4	S	Source
5	SS	Source Sense



## Absolute Maximum Rating ( $T_C = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter-Conditions	Value	Units
$V_{DS}$	Drain to Source Voltage (Note 1)	100	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	120	
$I_D$	Continuous Drain Current $I_D$ @ $V_{GS} = 5\text{ V}$	80	A
$I_{DM}$	Single-Pulse Drain Current $t_{pulse} = 300\ \mu\text{s}$	345	
$V_{GS}$	Gate to Source Voltage (Note 2)	+6 / -4	V
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to +150	°C
$T_{SOL}$	Package Mounting Surface Temperature	260	
ESD	ESD Class	$\Delta B$	

**Static Characteristics** (Typical (TYP) values are for reference only.)

Parameter	Symbol	Test Conditions	MIN	TYP	MAX	Units	
Drain to Source Voltage	$B_{VDSS}$	$V_{GS} = 0\text{ V}, I_D = 0.9\text{ mA}$	100			V	
Drain to Source Leakage	$I_{DSS}$	$V_{DS} = 100\text{ V}, V_{GS} = 0\text{ V}$		0.001	0.4	mA	
		$V_{DS} = 100\text{ V}, V_{GS} = 0\text{ V}$	$T_C = 125^\circ\text{C}$	0.01			
Gate to Source Forward Leakage	$I_{GSS}$	$V_{GS} = 5\text{ V}$		0.01	0.5		
Gate to Source Forward Leakage <sup>#</sup>		$V_{GS} = 5\text{ V}$	$T_C = 125^\circ\text{C}$	0.05			
Gate to Source Reverse Leakage		$V_{GS} = -4\text{ V}$	$T_C = 25^\circ\text{C}$	0.01	0.5		
Gate to Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 12\text{ mA}$	$T_C = 25^\circ\text{C}$	0.8	1.2	2.5	V
Gate to Source Threshold Voltage Temperature Coefficient	$\Delta V_{GS(th)}$		$-55^\circ\text{C} < T_A < 150^\circ\text{C}$		-1.9		mV/°C
Drain to Source Resistance (Note 4)	$R_{DS(on)}$	$V_{GS} = 5\text{ V}, I_D = 40\text{ A}$	$T_C = 25^\circ\text{C}$	5.2	6.0	mΩ	
Source to Drain Forward Voltage (Note 5)	$V_{SD}$	$I_S = 0.5\text{ A}, V_G = 0\text{ V}$	$T_C = 25^\circ\text{C}$	1.8		V	

All measurements were done with substrate shorted to source.

# Defined by design. Not subject to production test.

**Dynamic Characteristics** ( $T_C = 25^\circ\text{C}$  unless otherwise noted. Typical (TYP) values are for reference only.)

Parameter	Symbol	Test Conditions	MIN	TYP	MAX	Units
Input Capacitance	$C_{ISS}$	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		1240		pF
Reverse transfer Capacitance	$C_{RSS}$			5.7		
Output Capacitance	$C_{OSS}$			740		
Effective Output Capacitance, Energy Related	$C_{OSS(ER)}$	$V_{DS} = 0\text{ to }50\text{ V}, V_{GS} = 0\text{ V}$		970		
Effective Output Capacitance, Time Related	$C_{OSS(TR)}$			1250		
Total Gate Charge	$Q_G$	$V_{DS} = 50\text{ V}, V_{GS} = 5\text{ V}, I_D = 40\text{ A}$		11.7		nC
Gate to Source Charge	$Q_{GS}$	$V_{DS} = 50\text{ V}, I_D = 40\text{ A}$		4.0		
Gate to Drain Charge	$Q_{GD}$			2.1		
Output Charge (Note 6)	$Q_{OSS}$	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		63		
Source to Drain Recovery Charge	$Q_{RR}$			0		

All measurements were done with substrate shorted to source.

### Radiation Characteristics

EPC Space eGaN<sup>®</sup> HEMTs are tested according to MIL-STD-750 Method 1019 for total ionizing dose validation. Every manufacturing lot is tested for total ionizing dose of Gamma radiation with an in-situ bias for (i)  $V_{GS} = 5\text{ V}$ , (ii)  $V_{DS} = V_{GS} = 0\text{ V}$  and (iii)  $V_{DS} = 80\% B_{VDSS}$ .

**Electrical Characteristics up to 1000 krad ( $T_C = 25^\circ\text{C}$  unless otherwise noted. Typical (TYP) values are for reference only.)**

Parameter	Symbol	Test Conditions	MIN	TYP	MAX	Units
Maximum Drain to Source Voltage	$V_{DSMAX}$	$V_{GS} = 0\text{ V}, I_D = 0.9\text{ mA}$	100			V
Gate to Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 12\text{ mA}$	0.8	1.2	2.5	
Drain to Source Leakage	$I_{DSS}$	$V_{DS} = 100\text{ V}, V_{GS} = 0\text{ V}$		0.001	0.4	mA
Gate to Source Forward Leakage	$I_{GSS}$	$V_{GS} = 5\text{ V}$		0.01	0.5	
Gate to Source Reverse Leakage		$V_{GS} = -4\text{ V}$		0.01	0.5	
Drain to Source Resistance (Note 4)	$R_{DS(on)}$	$I_D = 40\text{ A}, V_{GS} = 5\text{ V}$		5.2	6.0	m $\Omega$

### Typical Single Event Effect Safe Operating Area

Note : All Single Event Effect testing is performed on the K-500 Cyclotron at Texas A&M University

Test	Environment			$V_{DS}$ Voltage (V)		
	Ion	LET MeV/mg/cm <sup>2</sup>	Range $\mu\text{m}$	Energy MeV	$V_{GS} = 0\text{ V}$	$V_{GS} = -4\text{ V}$
See SOA	Xe	50	131	1653	100	100
	Au	83.7	130	2482	100	100

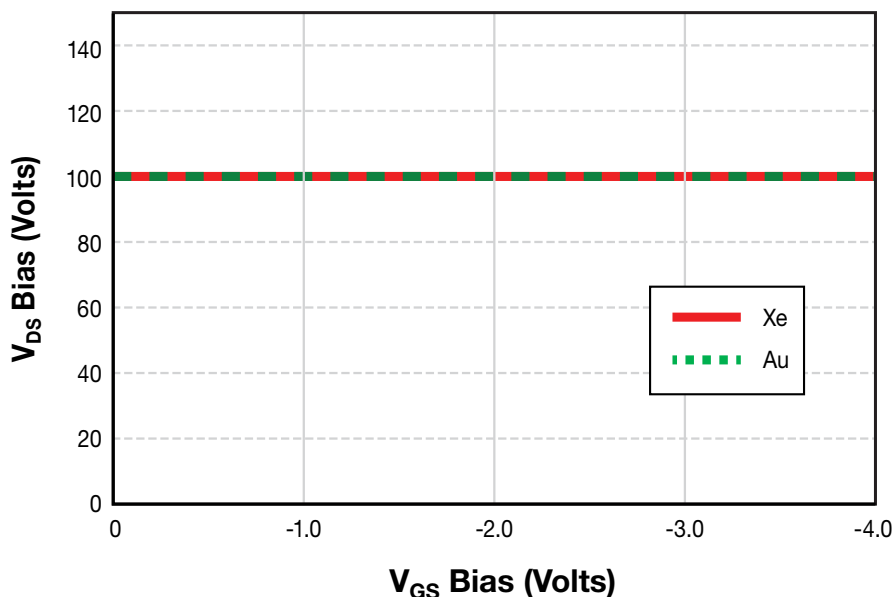


Figure 1: Typical Single Event Effect Safe Operating Area

Figure 2: Typical Output Characteristics at 25°C

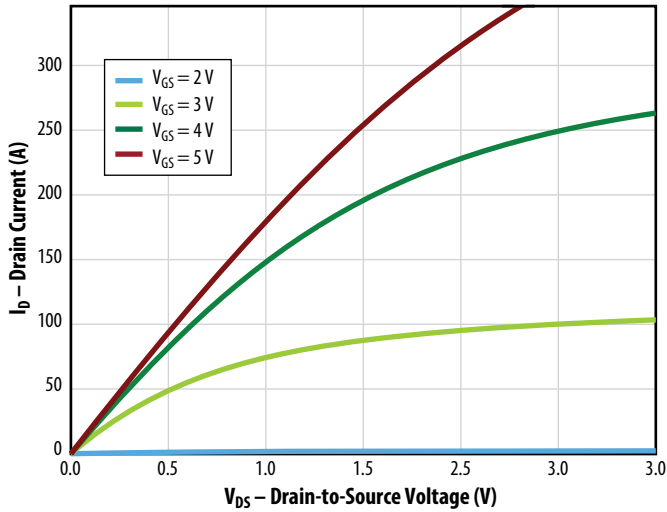


Figure 3: Typical Output Characteristics at 125°C

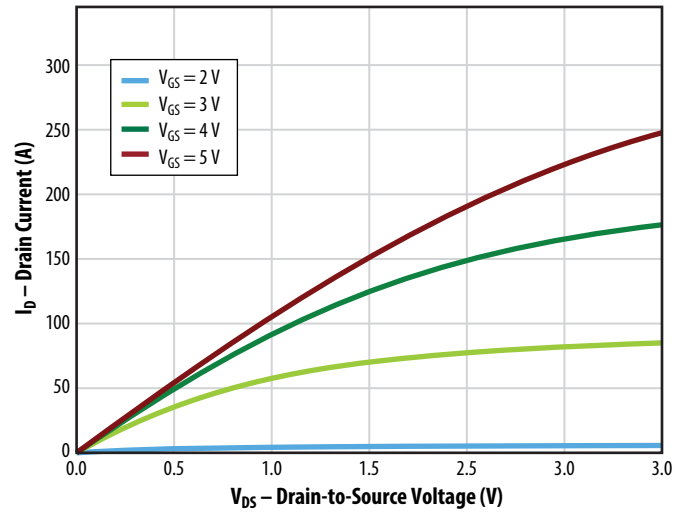


Figure 4: Typical Transfer Characteristics

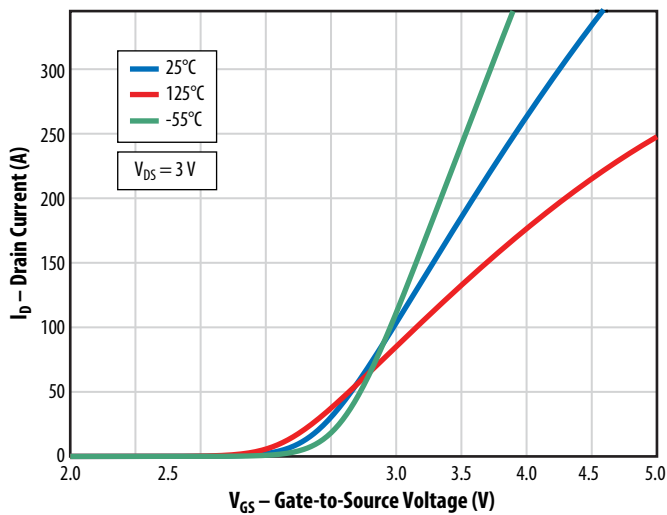


Figure 5:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

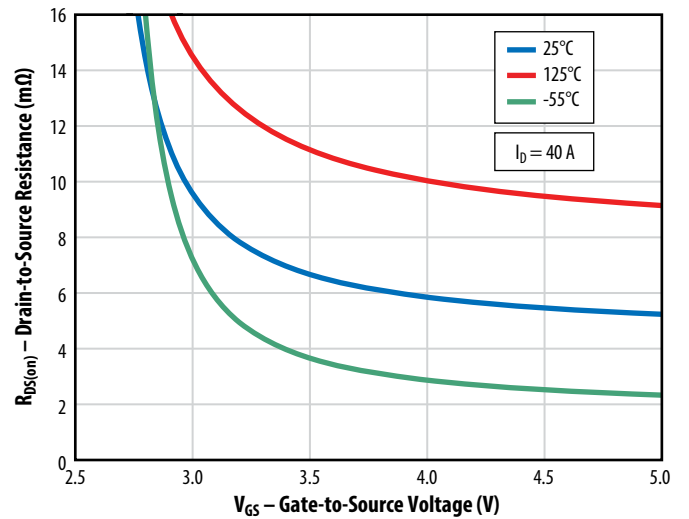


Figure 6:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents

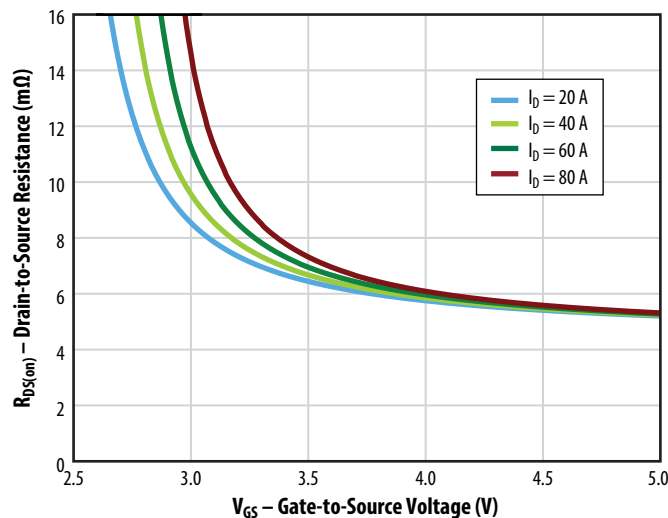


Figure 7: Normalized Threshold Voltage vs. Temperature

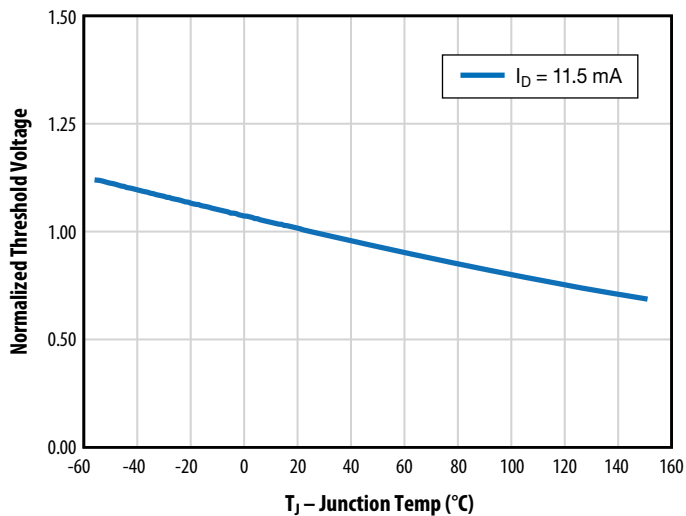


Figure 8: Normalized On-State Resistance vs. Temperature

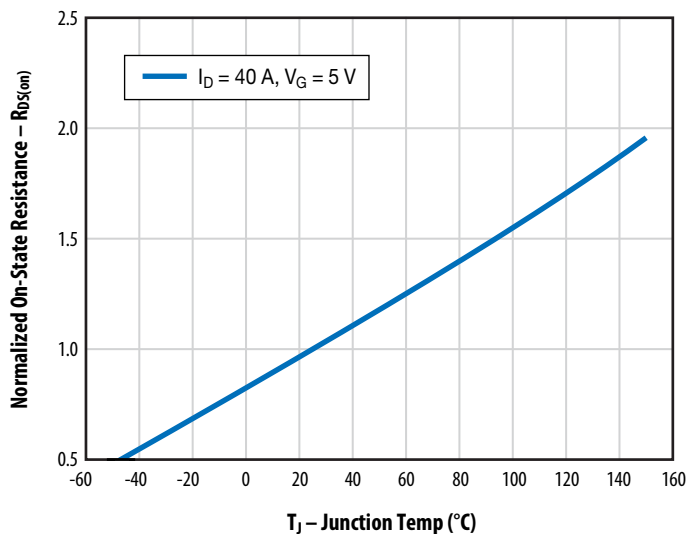


Figure 9: Typical Capacitance (Linear Scale)

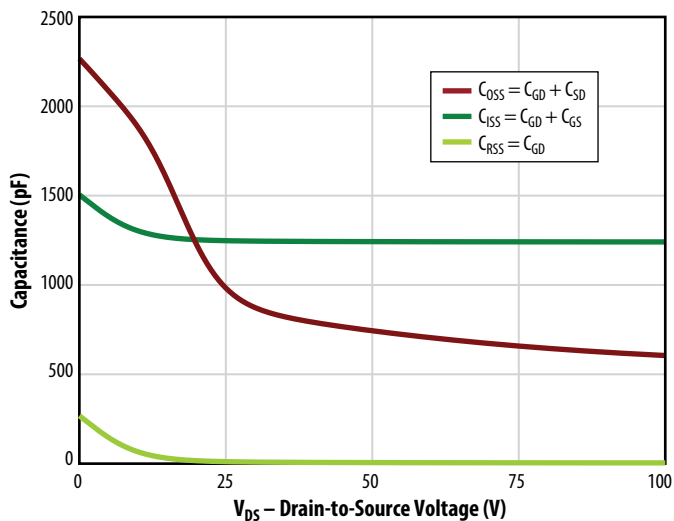


Figure 10: Typical Gate Charge

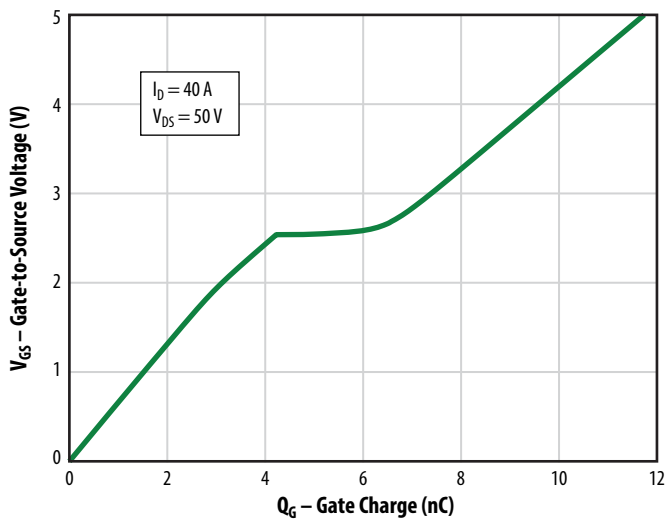
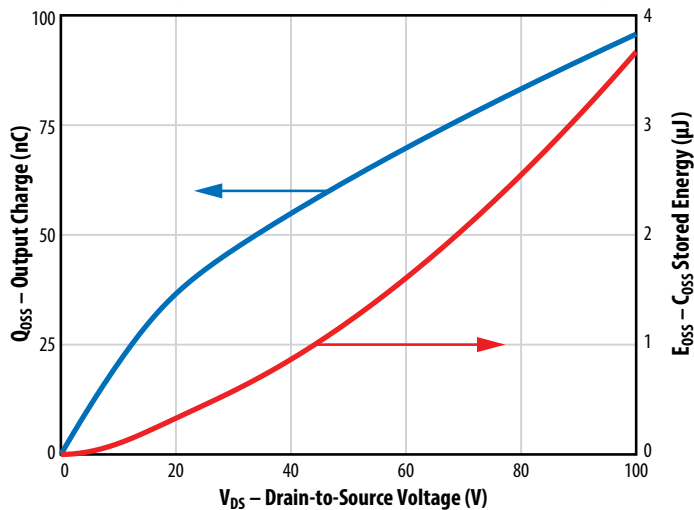
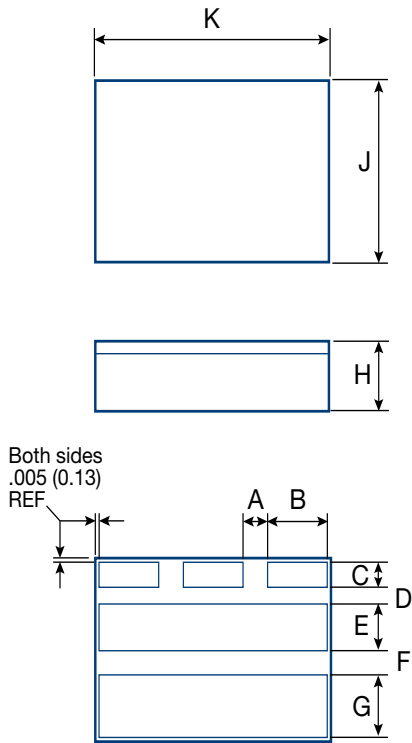


Figure 11: Typical Output Charge and Coss Stored Energy



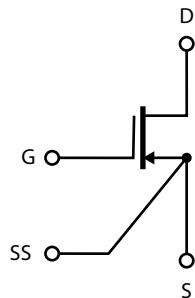
**Package Outline and Dimensions**



Symbol	Inches		Millimeters		Note
	MIN	MAX	MIN	MAX	
<b>A (2x)</b>	0.028	0.038	0.711	0.965	
<b>B (3x)</b>	0.075	0.085	1.905	2.159	
<b>C (3x)</b>	0.025	0.035	0.635	0.889	
<b>D</b>	0.015	0.025	0.381	0.635	
<b>E</b>	0.051	0.061	1.295	1.549	
<b>F</b>	0.024	0.034	0.61	0.864	
<b>G</b>	0.07	0.08	1.778	2.032	
<b>H</b>	0.078	0.088	1.981	2.235	
<b>J</b>	0.215	0.225	5.461	5.715	
<b>K</b>	0.311	0.321	7.899	8.153	

Standard Terminal Pad finish is a solder alloy of 63%Pb 37%Sn

**Package Connections**

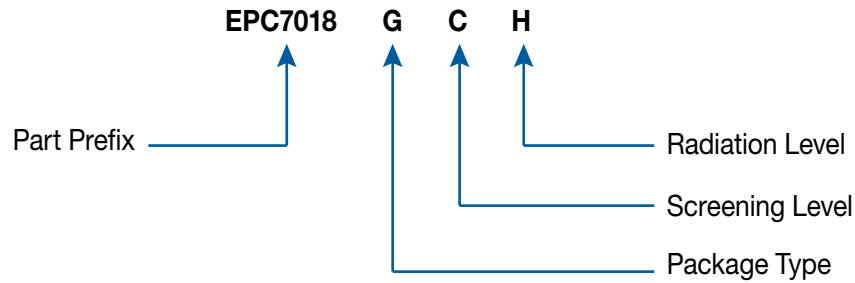


**NOTE:** SS pin is connected directly to source of internal die.

## Notes

- Note 1. NEVER exceed the absolute maximum  $V_{DS}$  of the device otherwise permanent damage/destruction may result.
- Note 2. NEVER exceed the absolute maximum  $V_{GS}$  of the device otherwise permanent damage/destruction may result. We recommend use at no greater than +5 V as the HEMT is fully conducting at this point.
- Note 3.  $R_{\theta JA}$  measured with LCC3 package mounted to double-sided PCB, 0.063" thickness with 1.0 square inches of copper area on the top (mounting side) and a flood etch (3 square inches) on the bottom side.
- Note 4. Measured using four wire (Kelvin) sensing and pulse measurement techniques. Measurement pulse width is 80  $\mu$ s and duty cycle is 1%, maximum.
- Note 5. Operation of the device in the third quadrant region is not recommended.
- Note 6. Guaranteed by design/device construction. Not tested.

### EPC Space Part Number Information



### Ordering Information Availability

Screening Options	Rad Assurance Options
1 character	1 character
C = Developmental Unit S = Space Level <sup>1</sup>	H = 1000 krad LET = 84

Part Number	Screening Level	Shipping
EPC7018GC	Developmental Units	Waffle trays
EPC7018GSH	Space Level	

<sup>1</sup> Screening and qualification consistent to an equivalent MIL-PRF-19500 specification.

EPC7018GC devices are intended for engineering development purposes only and are NOT intended to be used as flight units.

EPC Space Rad Hard HEMT are not sensitive to Total Ionizing Dose as such the H level covers the R,F,G radiation levels.



## Screening Flow Equivalent to a MIL-PRF-19500 General Specification

EPC SPACE Qual Flow Equivalent to a MIL-PRF-19500 Specification					
Operation	Test	Test Methods Per Mil STD 750	Sample Size	Space Level	COT
<b>Pre-Assembly</b>	Probe Testing	EPC SPACE Internal	100%	✓	✓
	Visual inspection	EPC SPACE Internal	100%	✓	✓
<b>Post-Assembly</b>	Die Shear	2,017	5	✓	✓
	X-Ray	2076	5	✓	✓
<b>Screening</b>	Serrialization		100%	✓	
	Electricals	3411,3413,3421,3404	100%	✓	✓
	Temp Cycling	1051	100%	✓	
	Constant Acceleration	2006	100%	✓	
	PIND	2052	100%	✓	
	Initial Electricals (Read and Record)	3411,3413,3421,3404	100%	✓	
	HTGB	1042 Condition B	100%	✓	
	Interim Electricals (Read and Record)	3411,3413,3421,3404	100%	✓	
	HTRB	1042 Condition A 240 Hours	100%	✓	
	Final Electricals (Read and Record)	3411,3413,3421,3404	100%	✓	
	Final Electricals (High and Low Temperatures)	3411,3413,3421,3404	100%	✓	
	Deltas	Per Procurement Specification	100%	✓	
	Percent Defective Allowable	Per Procurement Specification	100%	✓	
	Dynamic RDSON	EPC SPACE Internal	100%	✓	
	OutLiers Removal	EPC SPACE Internal	100%	✓	
	X-RAY	2076	100%	✓	
	Tinning		100%	✓	
	Hermetic Seal, Fine & Gross Leak	1071	100%	✓	
	Final Electricals	3411,3413,3421,3404	100%	✓	
	<b>Group A Inspection (Conformance)</b>	A-2 DC Static Tests at 25°C	3411,3413,3421,3404	116	✓
A-3 High & Low Temp DC Static Tests		3411,3413,3421,3404	116	✓	
A-7 Gate Charges		3471 Condition B	45	✓	
A-7 Capacitance		3473	45	✓	
<b>Group B Inspection (Conformance)</b>	B-1, B-2, B-3, B-4, B-5	Sample base equivalent to a MIL-PRF-19500 flow or as required by procurement speciffication			
<b>Group C Inspection (Conformance)</b>	C-1, C-2, C-3, C-4, C-6, C-7	Sample base performed yearly per package style equivalent to a MIL-PRF-19500 flow or as required by procurement specification			
<b>Group D Inspection (Conformance)</b>	TID	1019	15	✓	
	SEE	1080	5	✓	
<b>Group E Inspection (Qualification Inspection)</b>	E-1, E-2, E-5, E-6 E-7	Performed during product introduction or a major process change equivalent to a MIL-PRF-19500 flow or as required by procurement specification			
	E8 Switching				

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EPC Corporation and EPC Space hold numerous worldwide patents. Any that apply to the product(s) listed in this document are identified by markings on the product(s) or on internal components of the product(s) in accordance with local patent laws.

*eGaN<sup>®</sup> is a registered trademark of Efficient Power Conversion Corporation, Inc. Data and specification subject to change without notice.*

## Revisions

Datasheet Revision	Product Status
REV Q1	Characterization and Qualification
Preliminary	Production Released

Information subject to change without notice.

Revised February, 2023